## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | KRUPKA, EYAL | Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0118094	06-2003	Wang et al.	375/231
	В	US-2003/0091111	05-2003	Vaananen, Janne	375/231
	O	US-2002/0021750	02-2002	Belotserkovsky et al.	375/232
	D	US-6,002,716	12-1999	Meyer et al.	375/231
	Е	US-6,421,380	07-2002	Gu et al.	375/232
	F	US-5,475,710	12-1995	Ishizu et al.	375/232
	G	US-			
	н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	M	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	R					
	S					
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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